



Integrated Circuits for Physics Experiments

Microelectronic Group

Integrated Circuits for Physics Experiments

Outline

- Motivations
- ScalTech Project: Why 28nm technology?
- A Rail-to-Rail Input Chopper Instrumentation Amplifier
- IC-PIX28: Integrated Chip for PIXel read-out
- A Resistance-to-Frequency Interface for High DR Resistive Sensors

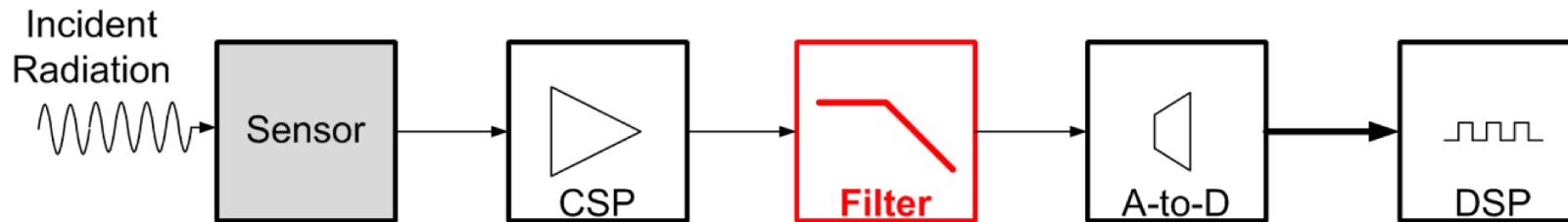
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Motivations

Design of integrated electronic interfaces for physics experiments



High-Energy-Physics Systems – Typical Blocks Scheme

- Typical Acquisition Path Blocks:
 - Charge-Sensitive-Preamplifiers
 - Analog Filters
 - Amplifiers
 - Analog to Digital Converters
 - Digital Signal Processing

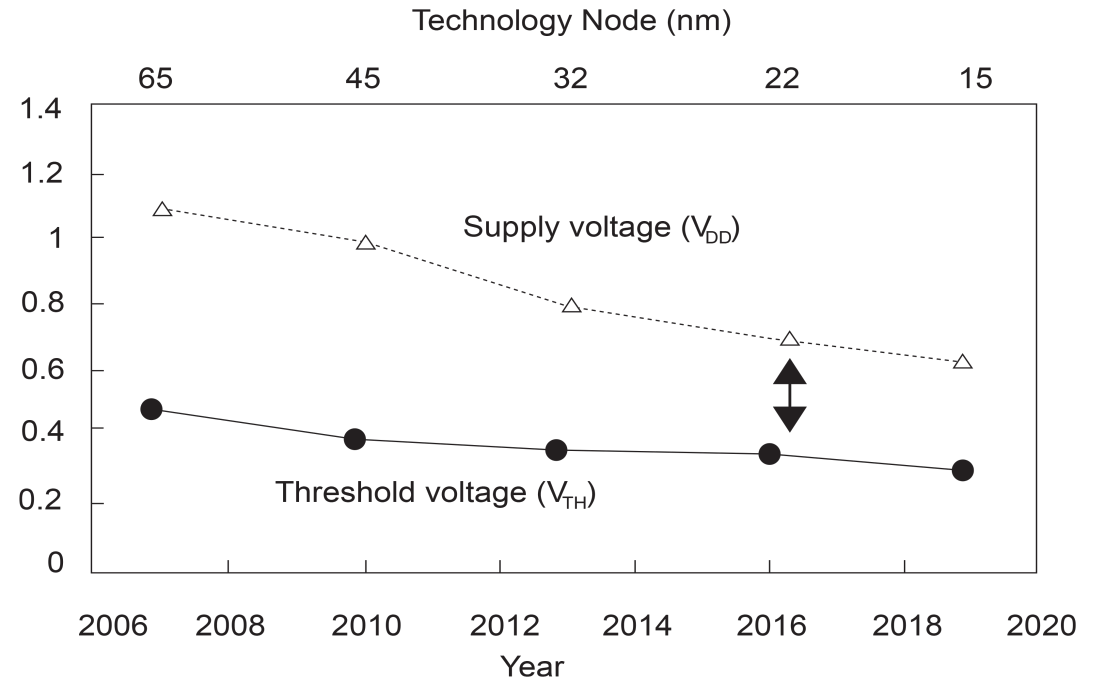
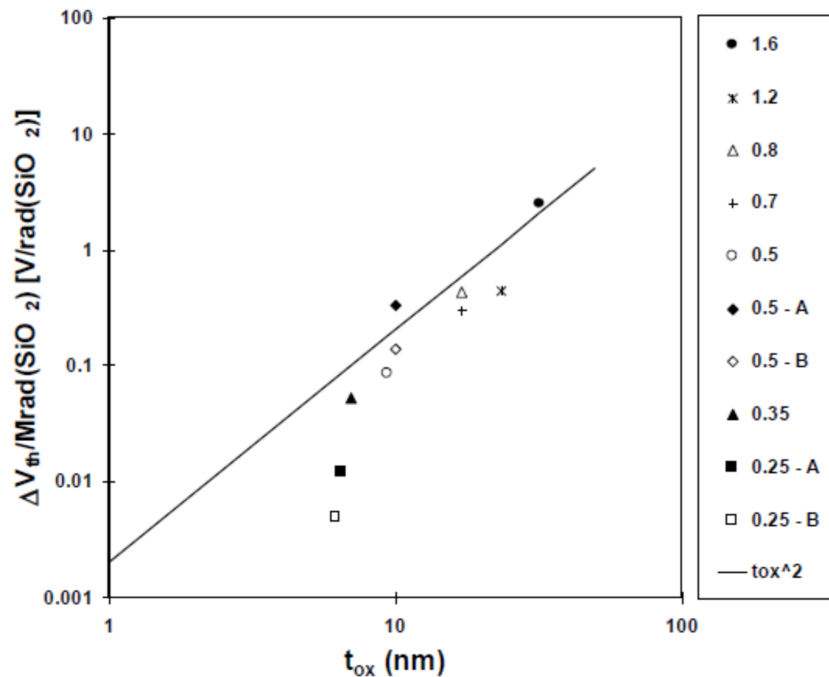
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Scaltech Project

Why 28nm technology?



• Pros:

- Radiation Hardness (to check with measurements)
- Higher integration
- Higher processing rate & more speed

• Cons:

- Lower V_{DD} to v_{th} ratio
- Lower signal swing
- Lower SNR
- Higher PVT variations

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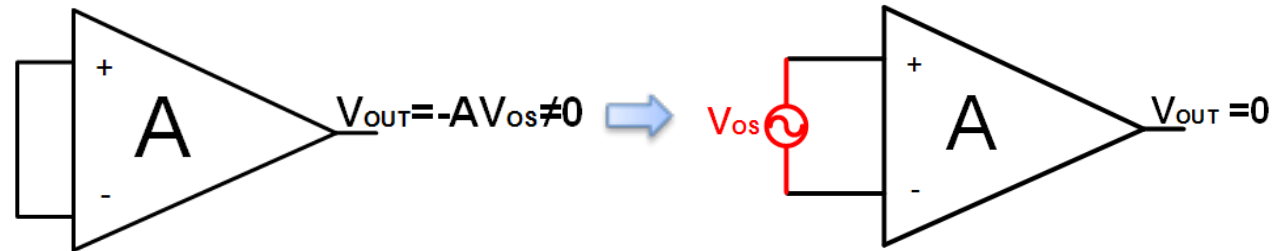
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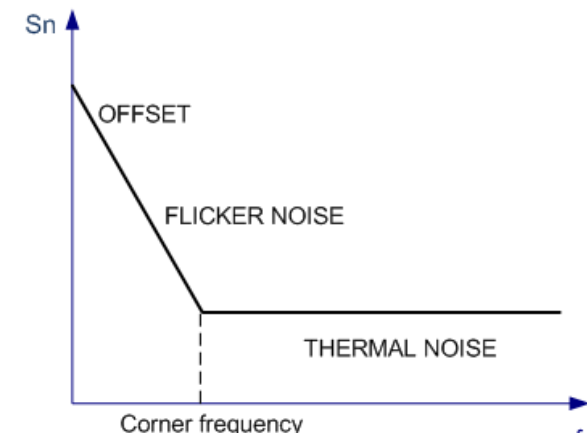
A Rail-to-Rail Input Chopper Instrumentation Amplifier

Offset & 1/f noise definition

- **Offset** is the signal that needs to be applied to the input to make the amplifier output equal to zero



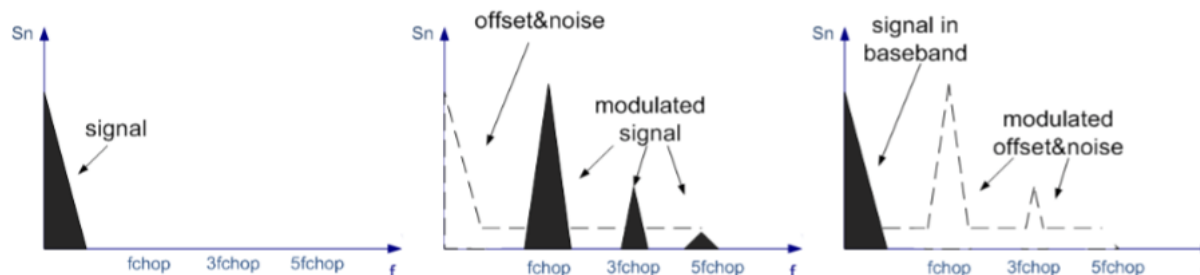
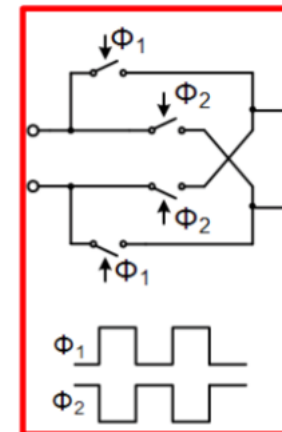
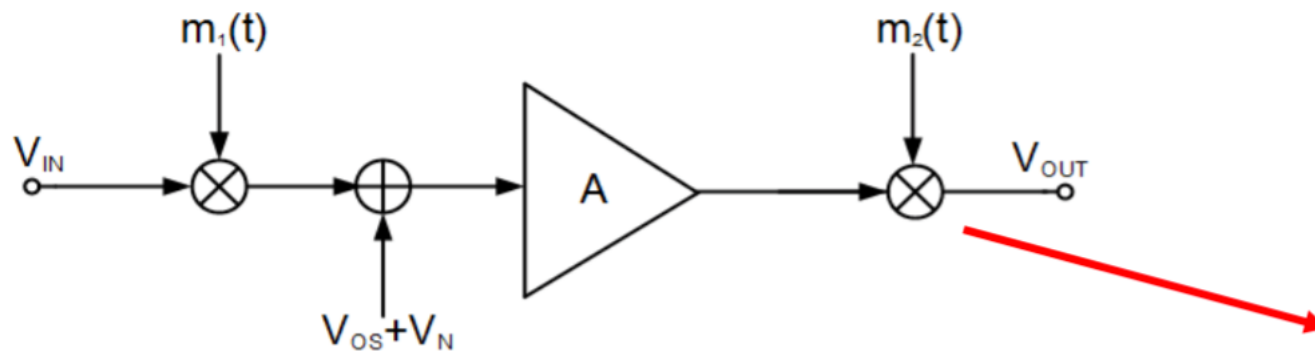
- Systematic offset
 - due to asymmetric paths
- Random offset
 - due to mismatch i.e. random variations of identical designed devices
 - threshold voltage V_{TH} and drain current I_D mismatches
- **Flicker (1/f) noise** energy is due to charge trapping in the discontinuity of the MOS gate oxide
 - Characterized by a large time constant
 - Concentrated at low frequency



A Rail-to-Rail Input Chopper Instrumentation Amplifier

Chopping Technique

- Signal is modulated, amplified and then demodulated again
- Offset & $1/f$ noise are modulated once $\rightarrow$ shifted to high frequency
- $m_i(t)$ is a square wave signal with period $T_{\text{chop}} = 1/f_{\text{chop}}$
- Modulator is a polarity reversing switch

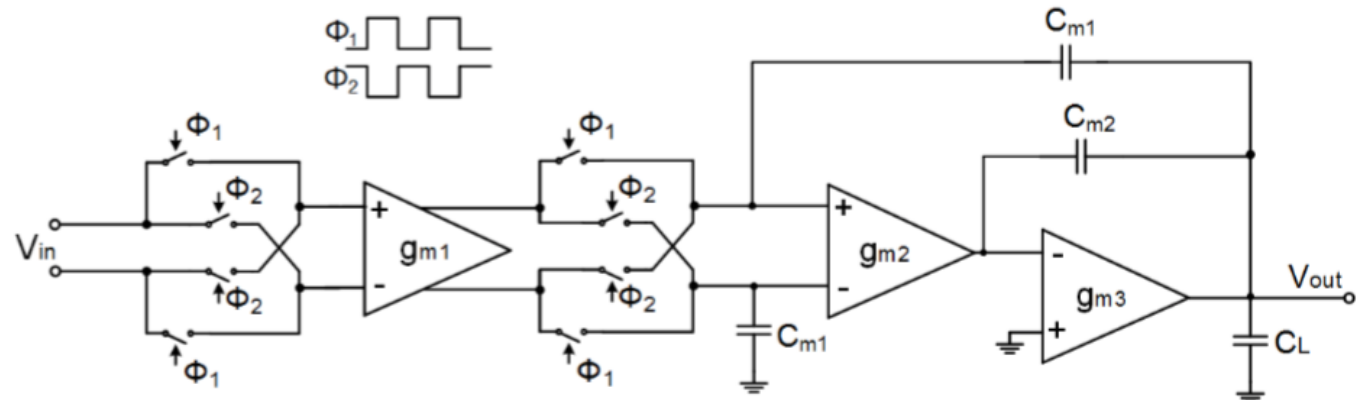


A Rail-to-Rail Input Chopper Instrumentation Amplifier

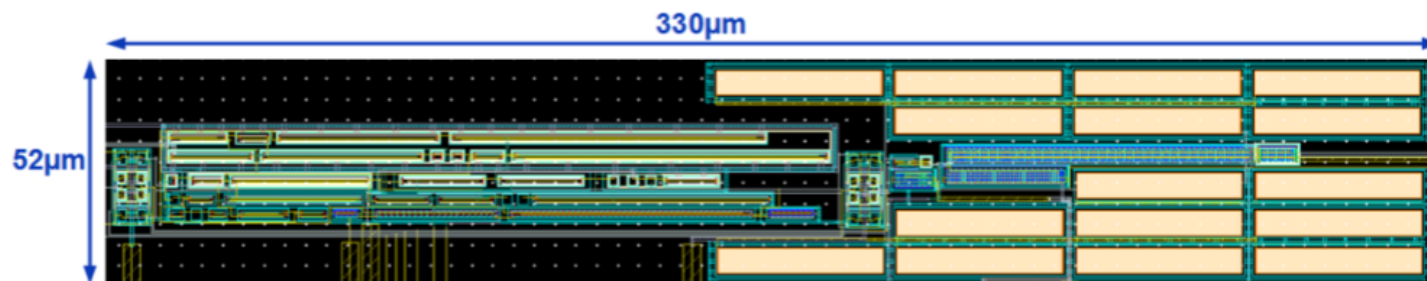
Circuit Schematic and Layout

- Design of an instrumentation amplifier (IA) characterized by:

- High gain
- Low offset
- Low flicker noise



- Typical dynamic offset cancellation technique: **Chopping technique**
- Three-stage chopper instrumentation amplifier
 - Thanks to chopping operation, offset and flicker noise are reduced
 - Scaled technology $\rightarrow$ Amplifier working in sub-threshold region



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IC-PIX28: Integrated Chip for PIXel read-out

Introduction

- Applications:

- Physics Experiments

- Photography

- CMOS Active Pixel Sensors (APSs)

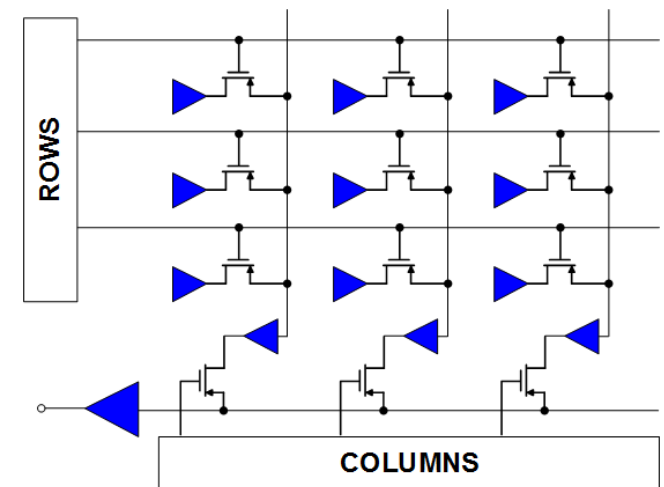
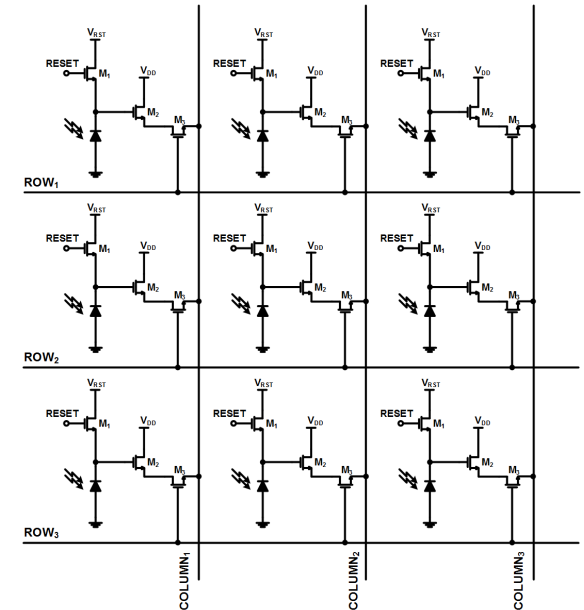
- Each pixel cell performs
 - Photon to Electron conversion
 - Charge to Voltage conversion
 - Sensor and read-out electronic are on-chip
 - More compatibility
 - More accuracy
 - More complex

- Input Charged particles:

- $0.1\text{fC} \div 6\text{fC}$ (very small charges)

- Conventional Pixel Structures:

- Matrix of n-rows and m-columns
 - Higher pixel cells to increase the resolution
 - Pixel cell smaller, low power and faster

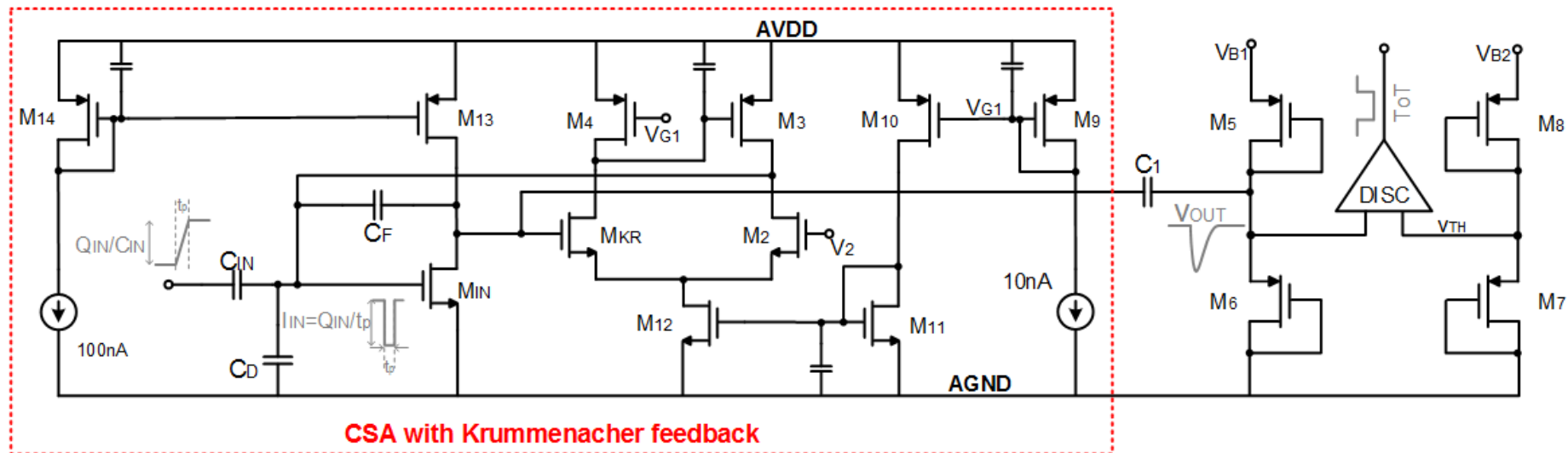
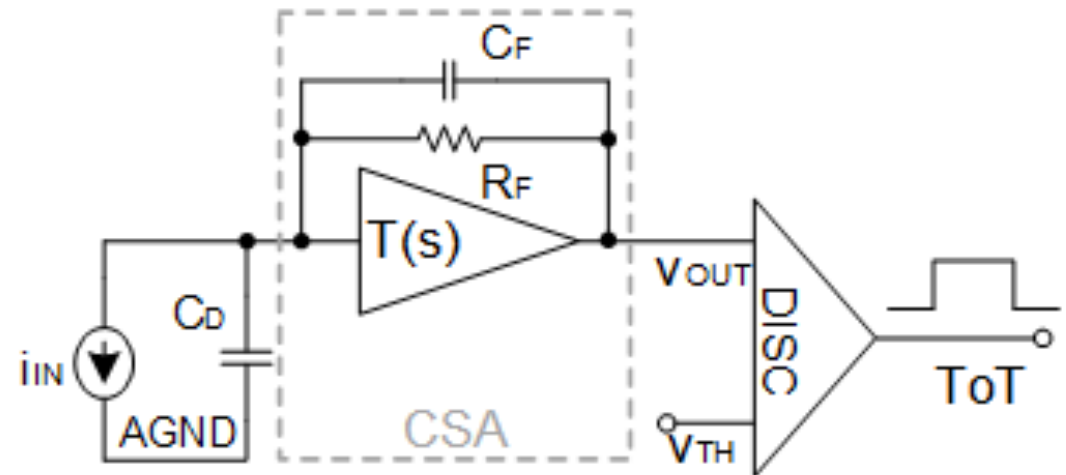


IC-PIX28: Integrated Chip for PIXel read-out

Prototype of one Channel

Output signals:

- Charge Sensitive Amplifier (CSA)
 - ➔ Charge to Voltage conversion
- Discriminator (DISC)
 - ➔ Voltage to Time conversion
 - ➔ Arrival time and amount of charge information



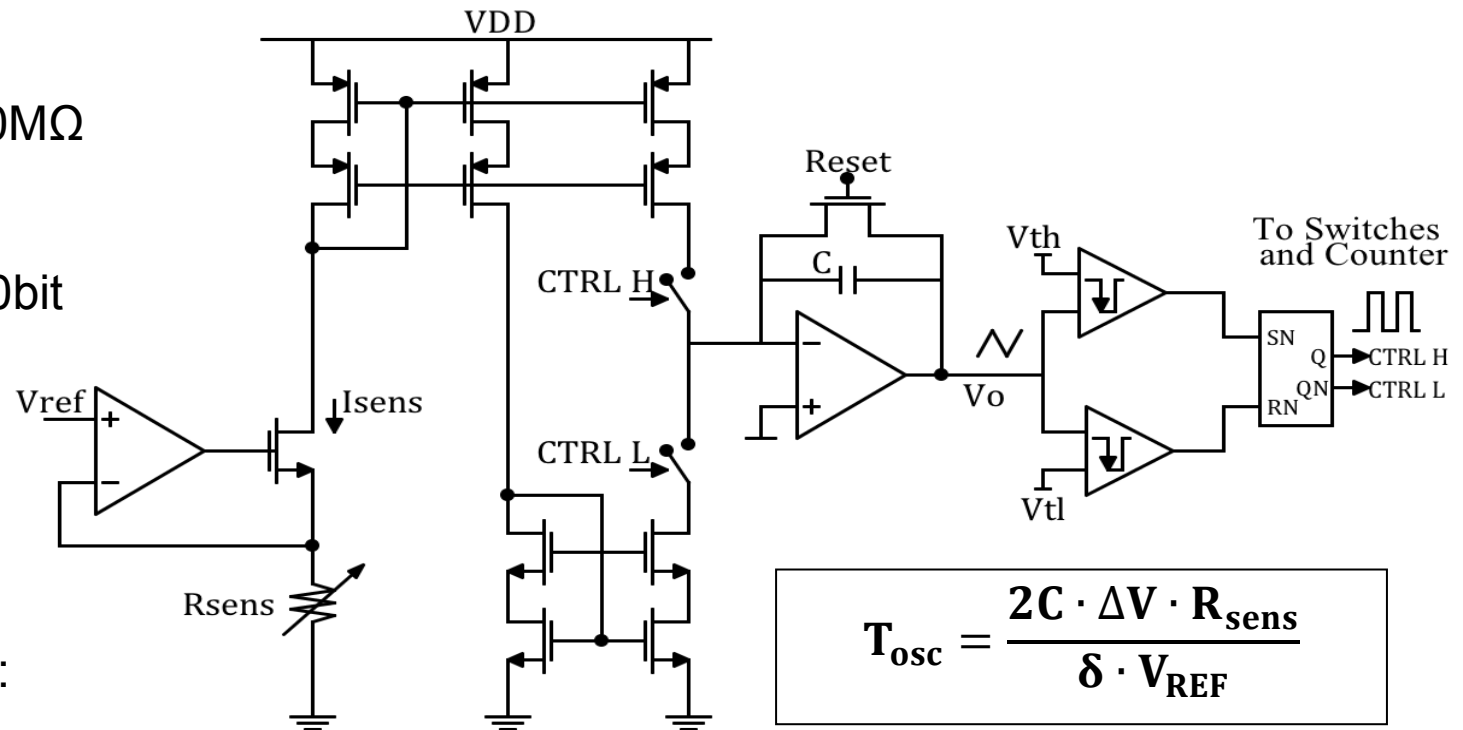
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A Resistance-to-Frequency Interface for High Dynamic Range Resistive Sensors

- Sensor range: 100Ω-10MΩ (100dB)
- equivalent precision: 10bit
- Max Current: 500μA



- Architecture Overview:
 - Voltage to current converter
 - Integrator
 - Comparators
 - Switches and Control Logic
 - Digital Output Counter

- Key Features:
 - Low Offset Opamp
 - Low Voltage, High linearity mirrors
 - fast Integrator and CT comparators
 - insensitive to Thermal noise

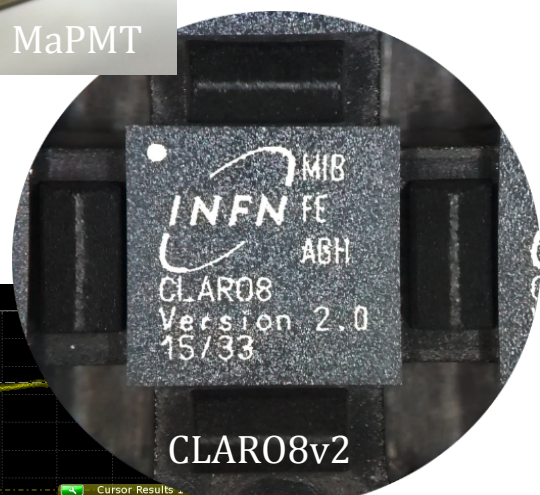


LHCb e CUORE

Gruppo Elettronica Analogica

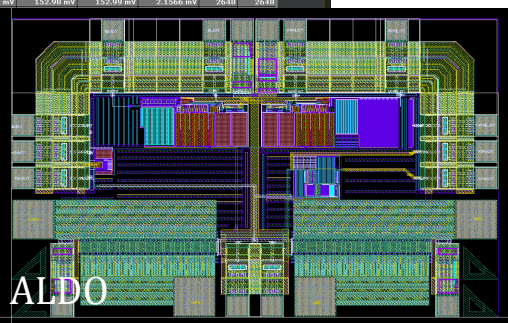
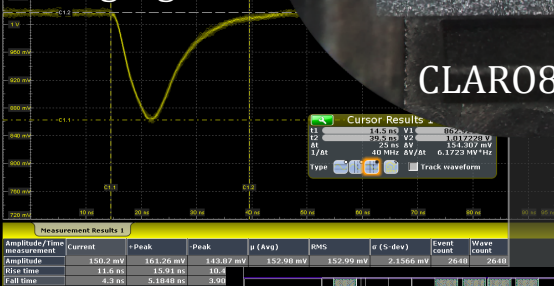


MaPMT



CLARO8v2

Single photon analog signal



ALDO

L'esperimento

- LHCb è l'esperimento dedicato allo studio della fisica del quark beauty e della violazione della simmetria CP

Rivelatore RICH

- I rivelatori RICH utilizzano l'effetto Cherenkov per misurare la velocità delle particelle e permetterne l'identificazione

Le attività del gruppo di elettronica analogica per il rivelatore RICH di LHCb

- Studio dei tubi fotomoltiplicatori a pixel MaPMT (conversione fotone → segnale elettrico)
- CLARO: progettazione del circuito integrato di lettura dei segnali analogici provenienti dai fototubi (segnale elettrico analogico → segnale digitale binario)
- ALDO: progettazione del circuito integrato (regolatore lineare) per la gestione dell'alimentazione del CLARO
- Testbeam: campagne di test della catena opto-elettronica eseguite presso l'acceleratore SPS al CERN

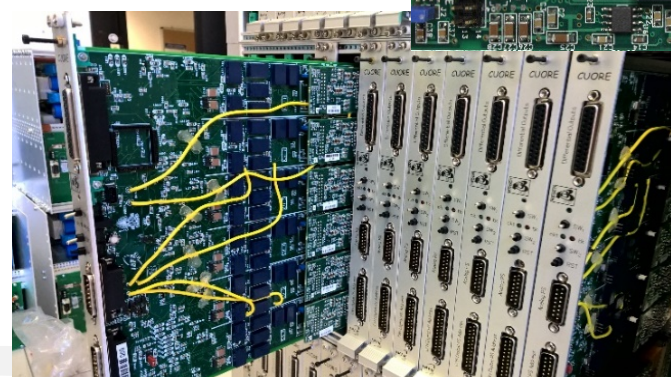
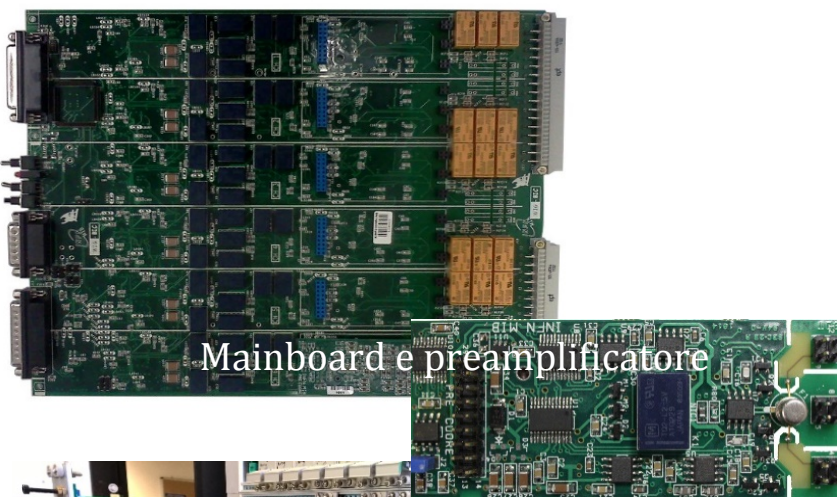


L'esperimento

- CUORE è un esperimento dedicato allo studio del doppio decadimento beta senza neutrini nel Tellurio-130
- Sfrutta la tecnica bolometrica: vengono misurate piccolissime variazioni di temperatura dovute al rilascio di energia nei rivelatori mantenuti a $T = 0.01\text{ K}$
- L'elettronica deve essere estremamente stabile e precisa. Per questo si preferisce un'elettronica discreta

Le attività del gruppo di elettronica analogica a LHCb

- Progettazione e test di tutta la catena di lettura, alimentazione e comunicazione (preamplificatore, amplificatore, filtro antialiasing, alimentatori lineari e DCDC, hub di comunicazione, impulsatore)



Per altre informazioni sulle attività del gruppo di elettronica analogica passate pure per una chiacchierata

- Gianluigi Pessina – Reference professor – U1 3040
- Claudio Gotti – Postdoc – U2 3032
- Lorenzo Cassina – PhD student – U1 3041
- Paolo Carniti – PhD student – U1 3041

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Thank you for your attention